

1 2. The method of claim 1, wherein the defect calibration scan data is performed  
2 on the occurrence of at least one of the group of events comprising when the image  
3 scanning device is powered up, upon request by a user, and periodically.

1 3. The method of claim 1, further comprising storing the tag.

1 4. The method of claim 3, further comprising repeating the steps of performing  
2 the defect calibration scanning, analyzing defect calibration scan data to detect for a  
3 new defect and a change in any previously detected defect, generating and storing a  
4 tag for each new detected defect, and updating the stored tag for each previously  
5 detected defect that has changed.

1 5. The method of claim 1, further comprising automatically compensating for the  
2 defect based on information contained within the tag.

1 6. The method of claim 1, further comprising determining the nature of the  
2 defect by recursively dividing the section of the image scanning area tagged as having  
3 a defect into subareas and analyzing each subarea in detail.

1 7. The method of claim 1, further comprising determining whether the section of  
2 the image scanning area tagged as having a defect is included in a target image region.

1 8. The method of claim 7, further comprising ignoring the section of the image  
2 scanning area tagged as having a defect if that section is determined not to be  
3 included in the target image region.

1 9. The method of claim 8, wherein the section of the image scanning area tagged  
2 as having a defect is ignored in autofitting the target image to the image scanning  
3 area.

1 10. The method of claim 8, wherein the section of the image scanning area tagged  
2 as having a defect is ignored in cloning the target image to produce multiple target  
3 images over the image scanning area.

1 11. The method of claim 8, wherein the section of the image scanning area tagged  
2 as having a defect is ignored in enlarging the target image to fit across multiple image  
3 scanning areas.

1 12. The method of claim 7, further comprising smoothing over the section of the  
2 image scanning area tagged as having a defect if that section is determined to be  
3 included in the target image region.

1 13. The method of claim 1, wherein the defect calibration scan is a low resolution  
2 scan.

1 14. An apparatus for automatically detecting defects in an image scanning device,  
2 comprising:

3 an analyzer for analyzing data produced from a defect calibration scan of an  
4 image scanning area by the image scanning device to detect at least one defect in at  
5 least one section of the image scanning area; and

6 a tag generator for generating a tag for each section of the image scanning area  
7 in which the defect is detected.

1 15. The apparatus of claim 14, wherein the defect calibration scan data is  
2 performed on the occurrence of one of the group of events comprising when the  
3 image scanning device is powered up, upon request by a user, and periodically.

1 16. The apparatus of claim 14, further comprising a memory for storing the tag.

1 17. The apparatus of claim 16, wherein the defect calibration scan is repeatedly  
2 produced, the analyzer for each repeated scan analyses the calibration scan data to  
3 detects a new defect and to detect a change in any previously detected defect, and the  
4 tag generator generates a tag for each new defect and updates the tag for each  
5 previously detected defect that has changed, and wherein the new tags and updated  
6 tags are stored in the memory .

1 18. The apparatus of claim 14, further comprising a compensator for  
2 compensating for the defect based on information contained within the tag.

1 19. The apparatus of claim 14, further comprising means for determining the  
2 nature of the defect by recursively dividing the section of the image scanning area  
3 tagged as having a defect into subareas and analyzing each subarea in detail.

1 20. The apparatus of claim 14, further comprising means for determining whether  
2 the section of the image scanning area tagged as having a defect is included in a target  
3 image region.

1 21. The apparatus of claim 20, further comprising means for ignoring the section  
2 of the image scanning area tagged as having a defect if that section is determined not  
3 to be included in the target image region.

1 22. The apparatus of claim 21, wherein the section of the image scanning area  
2 tagged as having a defect is ignored in autofitting the target image to the image  
3 scanning area.

1 23. The apparatus of claim 21, wherein the section of the image scanning area  
2 tagged as having a defect is ignored in cloning the target image to produce multiple  
3 target images over the image scanning area.

1 24. The apparatus of claim 21, wherein the section of the image scanning area  
2 tagged as having a defect is ignored in enlarging the target image to fit across multiple  
3 image scanning areas.

1 25. The apparatus of claim 20, further comprising means for smoothing over the  
2 section of the image scanning area tagged as having a defect if that section is  
3 determined to be included in the target image region.

1 26. The apparatus of claim 14, wherein the defect calibration scan is a low  
2 resolution scan.

1 27. The apparatus of claim 14, wherein the analyzer and the tag generator are  
2 included in the image scanning device.

1 28. The apparatus of claim 16, wherein the memory is included in the image  
2 scanning device.

1 29. The apparatus of claim 18, wherein the compensator is included in the image  
2 scanning device.

1 30. The apparatus of claim 14, wherein at least one of the analyzer and the tag  
2 generator are included in a host computer connected to the image scanning device.

1 31. The apparatus of claim 16, wherein the memory is included in a host computer  
2 connected to the image scanning device.

1 32. The apparatus of claim 18, wherein the compensator is included in a host  
2 computer connected to the image scanning device.